

THE COMMISSIONER IS AUTHORIZED  
TO CHARGE ANY DEFICIENCY IN THE  
FEE FOR THIS PAPER TO DEBIT  
ACCOUNT NO. 23-0975.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Akira TERAOKA

Serial No. NEW

Filed March 24, 2000

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Attn: APPLICATION BRANCH

Docket No. 2000\_0311A

X-RAY INSPECTION METHOD AND  
APPARATUS USED FOR THE SAME

#2  
Refined  
6-26-00

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents  
Washington, DC 20231

Sir:

Prior to examination of the above-referenced U.S. patent application please  
amend the application as follows:

IN THE CLAIMS:

Please amend the claims as follows:

- Claim 4, line 1, delete "or 2".  
Claim 8, line 1, delete "or 6".  
Claim 9, line 1, change "one of claims 5-8" to --Claim 5--.  
Claim 10, line 1, change "one of Claims 5-9" to --Claim 5--.

Please add the following new claims:

--12. A method of X-ray inspection according to Claim 2, wherein the straight line to be  
the central axis and the axis of rotation is set to be vertical to a stage on which the sample is  
placed.

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